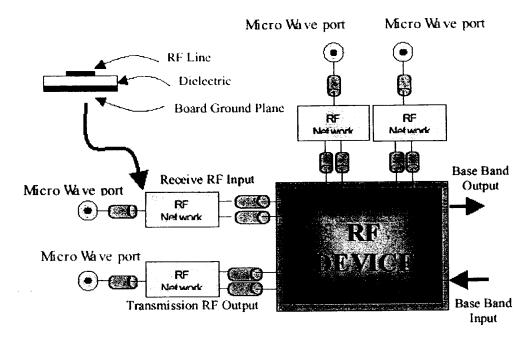
## TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS

Inventors: Giuseppe Di Gregorio et al. Express Mail No.: EV336599876US

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## REPLACEMENT SHEET



## FIG. 1

